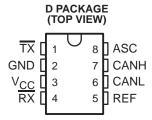
SLRS048A - MAY 1998 - REVISED APRIL 2000

- SN75LBC031 Meets Standard ISO/DIS 11898 (up to 500 k Baud)
- Driver Output Capability at 50 mA
- Wide Positive and Negative Input/output **Bus Voltage Range**
- **Bus Outputs Short-Circuit-Protected to Battery Voltage and Ground**
- **Thermal Shutdown**
- **Available in Q-Temp Automotive**
 - HighRel Automotive Applications
 - Configuration Control/Print Support
 - Qualification to Automotive Standards

description

The SN75LBC031 is a CAN transceiver used as an interface between a CAN controller and the physical bus for high speed applications of up to 500 kBaud. The device provides transmit capability to the differential bus and differential receive capability to the controller. The transmitter outputs (CANH and CANL), feature internal transition regulation to provide controlled symmetry resulting in low EMI emissions. Both



TERMINAL FUNCTIONS

TERMINAL	DESCRIPTION			
TX	Transmitter input			
GND	Ground			
V _{CC} Supply voltage				
RX	Receiver output			
REF	Reference output			
CANL	Low side bus output driver			
CANH	High side bus output driver			
ASC	Adjustable slope control			

FUNCTION TABLE

TX	CANH	CANL	BUS STATE	RX
L	Н	L	Dominant	L
High or floating	Floating	Floating	Recessive	Н

transmitter outputs are fully protected against battery short circuits and electrical transients that can occur on the bus lines. In the event of excessive device power dissipation the output drivers are disabled by the thermal shutdown circuitry at a junction temperature of approximately 160°C. The inclusion of an internal pullup resistor on the transmitter input ensures a defined output during power up and protocol controller reset. For normal operation at 500 kBaud the ASC terminal is open or tied to GND. For slower speed operation at 125 kBaud the bus output transition times can be increased to reduce EMI by connecting the ASC terminal to V_{CC}. The receiver includes an integrated filter that suppresses the signal into pulses less than 30 ns wide.

The SN75LBC031 is characterized for operation from -40°C to 85°C. The SN65LBC031 is characterized for operation from -40°C to 125°C. The SN65LBC031Q is characterized for operation over the automotive temperature range of -40°C to 125°C.

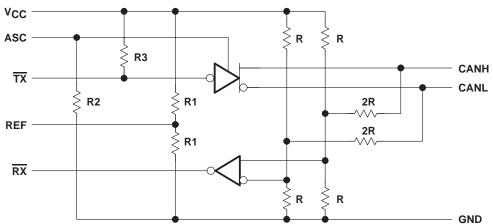


Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



SLRS048A - MAY 1998 - REVISED APRIL 2000

logic diagram



SLRS048A - MAY 1998 - REVISED APRIL 2000

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Logic supply voltage, V _{CC} (see Note 1)	7 V
Bus terminal voltage	
Input current at TX and ASC terminal, I ₁	±10 mA
Input voltage at TX and ASC terminal, V _I	$\dots \dots 2 \times V_{CC}$
Operating free-air temperature range, T _A : SN65LBC031, SN65LBC031Q	40°C to125°C
SN75LBC031	40°C to 85°C
Operating juncation range, T _J	40°C to 150°C
Continuous total power dissipation at (or below) 25°C free-air temperature Se	ee Dissipation Rating Table
Storage temperature range, T _{stq}	65°C to 150°C
Case temperature for 10 sec T _C , D package	260°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values, except differential bus voltage, are measured with respect to GND.

DISSIPATION RATING TABLE

PACKAGE	$T_{\mbox{\scriptsize A}} \le 25^{\circ}\mbox{\scriptsize C}$ POWER RATING	OPERATING FACTOR ABOVE T _C = 25°C	T _C = 125°C POWER RATING
D	725 mW	5.8 mW/°C	145 mW

DISSIPATION DERATING CURVE

vs

FREE-AIR TEMPERATURE

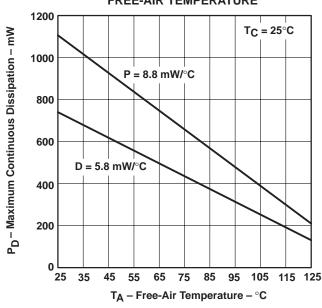


Figure 1

SLRS048A - MAY 1998 - REVISED APRIL 2000

recommended operating conditions

		MIN	NOM	MAX	UNIT
Logic supply voltage, V _{CC}	4.5	5	5.5	V	
Voltage at any bus terminal (separate	ly or common mode), V _I or V _{IC} (see Note 3)	-2		7	V
High-level input voltage, VIH	High-level input voltage, V _{IH} TX				
Low-level input voltage, V _{IL}	TX	0		0.8	V
High level entered entered leve	Transmitter			-50	mA
High-level output current, IOH	Receiver			-400	μΑ
Low lovel output ourrent lov	Transmitter			50	A
Low-level output current, IOL	Receiver			1	mA
Operating free-air temperature, TA	SN75LBC031	-40		85	°C
	SN65LBC031, SN65LBC031Q	-40		125	-0

NOTES: 2. All voltage values, except differential bus voltage, are measured with respect to the ground terminal.

3. For bus voltages from -5 V to -2 V and 7 V to 20 V the receiver output is stable.

SYMBOL DEFINITION

DATA SHEET PARAMETER	DEFINITION
VO(CANHR)	CANH bus output voltage (recessive state)
VO(CANLR)	CANL bus output voltage (recessive state)
VO(CANHD)	CANH bus output voltage (dominant state)
VO(CANLD)	CANL bus output voltage (dominant state)
VO(DIFFR)	Bus differential output voltage (recessive state)
V _{O(DIFFD)}	Bus differential output voltage (dominant state)
V _I (ASC)	Adjustable slope control input voltage

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
VO(REF)	Reference source output voltage	I _{REF} = ±20 μA	0.45 V _{CC}		0.55 V _{CC}	V
R _{O(REF)}	Reference source output resistance		5		10	kΩ
ICC(REC)	Logic supply current, recessive state	See Figure 2, S1 closed		12	20	mA
ICC(DOM)	Logic supply current, dominant state	See Figure 2, ST Closed		55	80	IIIA

SLRS048A - MAY 1998 - REVISED APRIL 2000

transmitter electrical characteristics over recommended ranges of supply and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
VO(CANHR) VO(CANLR)	Output voltage (recessive state)	See Figure 2, S1 open	2	0.5V _{CC}	3	V
V _{O(DIFFR)}	Differential output voltage (recessive state)		-500	0	50	mV
VO(CANHD)	Output voltage (dominant state)		2.75	3.5	4.5	
VO(CANLD)	Output voltage (dominant state)	See Figure 2, S1 closed	0.5	1.5	2.25	V
VO(DIFFD)	Differential output voltage (dominant state)		1.5	2	3	
	High-level input current (TX)	V _{IH} = 2.4 V		-100	-185	^
I _{IH} (TX)	righ-lever input current (1%)	VIH = VCC			±2	μΑ
lu va ees	High-level input current (ASC)	V _{IH} = 2.4 V		100	165	μΑ
IH(ASC)	righ-level input current (ASC)	V _{IH} = V _{CC}		200	340	μΑ
I _{IL(TX)}	Low-level input current (\overline{TX})	V _{IL} = 0.4 V		-180	-400	μΑ
IL(ASC)	Low-level input current (ASC)	V _{IL} = 0.4 V		15	25	μΑ
C _{I(TX)}	TX input capacitance			8		pF
I _{O(ssH)}	CANH short circuit output current	$V_{O(CANH)} = -2 V \text{ to } 20 V$		-95	-200	mA
I _{O(ssL)}	CANL short circuit output current	V _{O(CANL)} = 20 V to −2 V		140	250	mA

NOTE 2: All voltage values, except differential bus voltage, are measured with respect to the ground terminal.

transceiver dynamic characteristics over recommended operating free-air temperature range and V_{CC} = 5 V

	PARAMETER	TEST	CONDITIONS	MIN	TYP	MAX	UNIT
	Loop time	See Figures 2 and 3, S1 closed,	VI(ASC) = 0 V or open circuit, S2 open			280	ns
^t (loop)	Loop time	See Figures 2 and 3, S1 closed,	V _I (ASC) = V _{CC} , S2 closed			400	ns
SR _(RD)	Differential-output slew rate	See Figures 2 and 4, S1 closed,	V _I (ASC) = 0 or open circuit, S2 open		35		V/μs
	(recessive to dominant)	See Figures 2 and 4, S1 closed,	VI(ASC) = VCC, S2 closed		10		V/μs
CD	Differential-output slew rate	See Figures 2 and 4, S1 closed,	V _I (ASC) = 0 or open circuit, S2 open		10		V/μs
SR _(DR)	(dominant to recessive)	See Figures 2 and 4, S1 closed,	VI(ASC) = VCC, S2 closed		10		V/μs
t _d (RD)	Differential output delay time	San Figure 2	S1 closed		55		ns
t _d (DR)	Differential-output delay time	See Figure 2,	ST Closed		160		ns
tpd(RECRD)	Receiver propagation delay	See Figures 2 and 5			90		ns
tpd(RECDR)	time	Gee i igules 2 aliu 5			55		ns

NOTE 4: Receiver input pulse width should be >50 ns. Input pulses of <30 ns are suppressed.

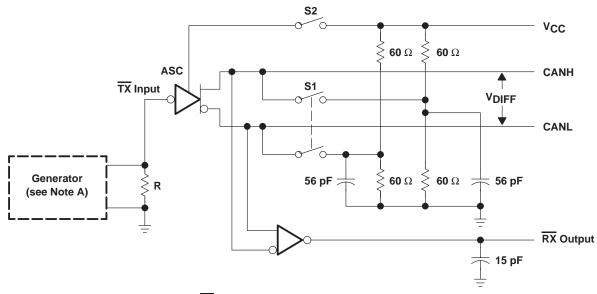
SLRS048A - MAY 1998 - REVISED APRIL 2000

receiver electrical characteristics over recommended ranges of common-mode input voltage, supply voltage, and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
VIT(REC)	Differential input threshold voltage for recessive state	V _{IC} = -2 V to 7 V			500	mV
VIT(DOM)	Differential input threshold voltage for dominant state	VIC = -2 V 10 7 V	900			IIIV
V _{hys}	Recessive-dominant input hysteresis		100	180		mV
VOH(RX)	High-level output voltage	$V_{O(DIFF)} = 500 \text{ mV},$ $I_{OH} = -400 \mu\text{A}$	V _{CC} -0.5 V		VCC	V
V _{OL(RX)}	Low-level output voltage	$V_{O(DIFF)} = 900 \text{ mV},$ $I_{OL} = 1 \text{ mA}$	0		0.5	V
rI(REC)	CANH and CANL input resistance in recessive state	dc, no load	5		50	kΩ
rI(DIFF)	Differential CANH and CANL input resistance in recessive state	dc, no load	10		100	kΩ
Ci	CANH and CANL input capacitance			20		pF
C _{i(DHL)}	Differential CANH and CANL input capacitance			10		pF

NOTE 2: All voltage values, except differential bus voltage, are measured with respect to the ground terminal.

PARAMETER MEASUREMENT INFORMATION



NOTE A: The input pulse is supplied to \overline{TX} by a generator having a t_f and $t_f = 5$ ns.

Figure 2. Test Circuit

PARAMETER MEASUREMENT INFORMATION

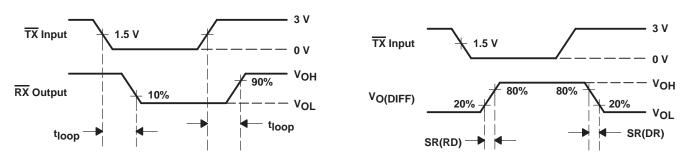
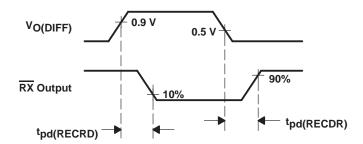


Figure 3. Loop Time

Figure 4. Slew Rate

NOTE A: The input pulse is supplied to \overline{TX} by a generator having a t_{Γ} and $t_{f} = 5$ ns.



NOTE A: The input pulse is supplied as V_{DIFF} using CANH and CANL respectively by a generator having a t_r and $t_f = 5$ ns.

Figure 5. Receiver Delay Times

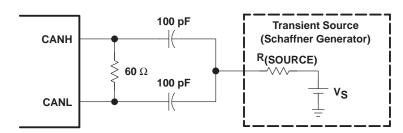


Figure 6. Transient Stress Capability Test Circuit

PARAMETER MEASUREMENT INFORMATION

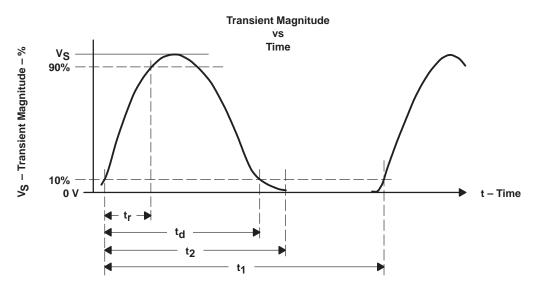


Figure 7. Transient Stress Capability Waveform

Table 1. Test Circuit Results According to DIN 40839

TEST PULSE	TRANSIENT MAGNITUDE VS	SOURCE IMPEDANCE RSOURCE	PULSE WIDTH t _d (see Note 5)	PULSE RISE TIME, t _r (see Note 6)	PULSE TIME, t ₂ (see Figure 7)	REPETITION PERIOD, t ₁ (see Figure 7)	NUMBER OF PULSES
1	–100 V	10 Ω	2 ms	1 μs	200 ms	5 s	5000
2	100 V	10 Ω	50 μs	1 μs	200 ms	5 s	5000
3a	−150 V	50 Ω	0.1 μs	5 ns	100 μs	100 μs	See Note 7
3b	100 V	50 Ω	0.1 μs	5 ns	100 μs	100 μs	See Note 7
5	60 V	1 Ω	400 ms	5 ms	_	_	1

NOTES: 5. Measured from 10% on rising edge to 10% on falling edge

- 6. Measured from 10% to 90% of pulse
- 7. Pulse package for a period of 3600 s, 10 ms pulse time, 90 ms stop time

SLRS048A - MAY 1998 - REVISED APRIL 2000

APPLICATION INFORMATION 5 V 💳 100 nF 3 120 Ω \lesssim 10 k Ω 10 kΩ § 8 **VCC VCC** 8 **ASC** TL7705B **CANH** 7 SENSE SN75LBC031 RESIN RESET GND CANL REF **GND** c_{in} TX REF RX 120 Ω 5 0.1 μF4 **CAN Microcontroller**

Figure 8. Typical SN75LBC031 Application

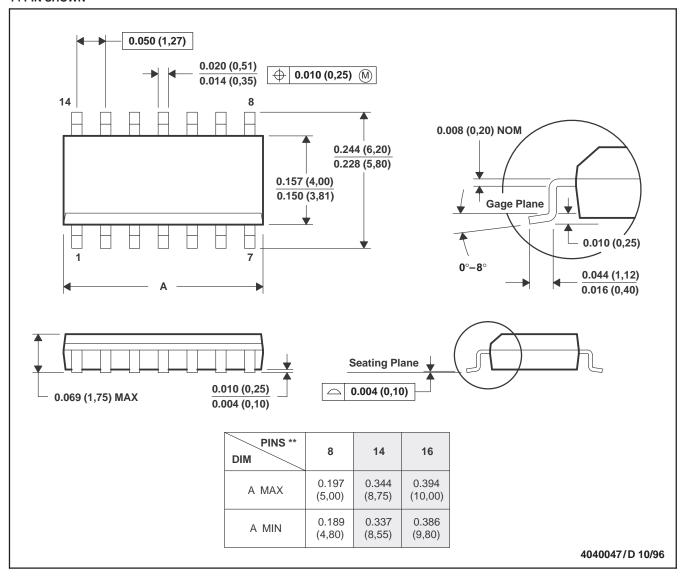
SLRS048A - MAY 1998 - REVISED APRIL 2000

MECHANICAL DATA

D (R-PDSO-G**)

14 PIN SHOWN

PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion, not to exceed 0.006 (0,15).

D. Falls within JEDEC MS-012

www.ti.com 12-Apr-2023

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing		Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
SN65LBC031D	LIFEBUY	SOIC	D	8	75	RoHS & Green	NIPDAU	Level-1-220C-UNLIM	-40 to 85	6LB031	
SN65LBC031DG4	LIFEBUY	SOIC	D	8	75	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	6LB031	
SN65LBC031DRG4	LIFEBUY	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM		6LB031	
SN65LBC031QD	LIFEBUY	SOIC	D	8	75	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	6LB031Q	
SN65LBC031QDR	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	LB031Q	Samples
SN75LBC031D	LIFEBUY	SOIC	D	8	75	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	7LB031	
SN75LBC031DR	LIFEBUY	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	7LB031	

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.



PACKAGE OPTION ADDENDUM

www.ti.com 12-Apr-2023

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

PACKAGE MATERIALS INFORMATION

www.ti.com 5-Dec-2023

TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN65LBC031QDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
SN75LBC031DR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1

PACKAGE MATERIALS INFORMATION

www.ti.com 5-Dec-2023



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN65LBC031QDR	SOIC	D	8	2500	350.0	350.0	43.0
SN75LBC031DR	SOIC	D	8	2500	350.0	350.0	43.0

PACKAGE MATERIALS INFORMATION

www.ti.com 5-Dec-2023

TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
SN65LBC031D	D	SOIC	8	75	505.46	6.76	3810	4
SN65LBC031DG4	D	SOIC	8	75	505.46	6.76	3810	4
SN65LBC031QD	D	SOIC	8	75	505.46	6.76	3810	4
SN75LBC031D	D	SOIC	8	75	505.46	6.76	3810	4



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES:

- 1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
- 4. This dimension does not include interlead flash.
- 5. Reference JEDEC registration MS-012, variation AA.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATA SHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.

TI objects to and rejects any additional or different terms you may have proposed.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2023, Texas Instruments Incorporated